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PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Inventors: Jon Opsal, et al.

Application No.: 10/659,626

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For: MODULATED REFLECTANCE  
MEASUREMENT SYSTEM USING  
UV PROBE

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Group Art Unit: 2877

Examiner: Unknown

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(37 CFR 1.8(a))**

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